AOK75B60D1

600V,75A Alpha IGBT™ with Diode

General Description

- AlphaIGBT (α IGBT) technology
- Low $V_{CE(SAT)}$ enables high efficiencies
- Smooth Switching waveforms reduce EMI
- Better thermal management
- Minimal gate spike under high dv/dt

Applications

- Welding Machines
- Solar Inverters
- Uninterruptible Power Supplies

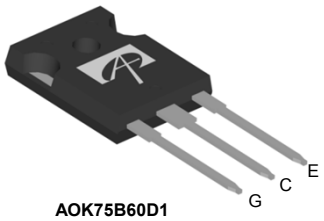
Product Summary

V_{CE}	600V
I_C (T_C=100°C)	75A
$V_{CE(sat)}$ (T_J=25°C)	1.72V

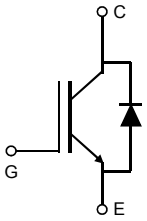
RoHS Compliant

Top View

TO-247



AOK75B60D1



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOK75B60D1	TO247	Tube	240

Absolute Maximum Ratings T_A=25°C unless otherwise noted

Parameter		Symbol	AOK75B60D1	Units
Collector-Emitter Voltage		V_{CE}	600	V
Gate-Emitter Voltage		V_{GE}	±20	V
Continuous Collector Current	T_C=25°C	I_C	150	A
	T_C=100°C		75	
Pulsed Collector Current, Limited by T_{Jmax}		I_{CM}	290	A
Turn off SOA, V_{CE} ≤ 600V, Limited by T_{Jmax}		I_{LM}	290	A
Continuous Diode Forward Current	T_C=25°C	I_F	75	A
	T_C=100°C		37.5	
Diode Pulsed Current, Limited by T_{Jmax}		I_{FM}	290	A
Short circuit withstanding time 1) V_{GE}=15V, V_{CE}≤400V, T_J≤175°C		t_{SC}	10	µs
Power Dissipation	T_C=25°C	P_D	600	W
	T_C=100°C		300	
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 175	°C
Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds		T_L	300	°C

Thermal Characteristics

Parameter	Symbol	AOK75B60D1	Units
Maximum Junction-to-Ambient	$R_{\theta JA}$	40	°C/W
Maximum IGBT Junction-to-Case	$R_{\theta JC}$	0.25	°C/W
Maximum Diode Junction-to-Case	$R_{\theta JC}$	0.95	°C/W

1) Allowed number of short circuits: <1000; time between short circuits: >1s.

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Typ	Max	Units
STATIC PARAMETERS							
BV_{CES}	Collector-Emitter Breakdown Voltage	I_C=1mA, V_{GE}=0V, T_J=25°C		600	-	-	V
$V_{CE(sat)}$	Collector-Emitter Saturation Voltage	V_{GE}=15V, I_C=75A	T_J=25°C	-	1.72	2.1	V
			T_J=125°C	-	2	-	
			T_J=175°C	-	2.3	-	
V_F	Diode Forward Voltage	V_{GE}=0V, I_F=37.5A	T_J=25°C	-	1.44	2	V
			T_J=125°C	-	1.43		
			T_J=175°C	-	1.37	-	
$V_{GE(th)}$	Gate-Emitter Threshold Voltage	V_{CE}=5V, I_C=1mA		-	5.35	-	V
I_{CES}	Zero Gate Voltage Collector Current	V_{CE}=600V, V_{GE}=0V	T_J=25°C	-	-	10	µA
			T_J=125°C	-	-	1250	
			T_J=175°C	-	-	15000	
I_{GES}	Gate-Emitter leakage current	V_{CE}=0V, V_{GE}=±20V		-	-	±100	nA
g_{FS}	Forward Transconductance	V_{CE}=20V, I_C=75A		-	36	-	S
DYNAMIC PARAMETERS							
C_{ies}	Input Capacitance	V_{GE}=0V, V_{CE}=25V, f=1MHz		-	4750	-	pF
C_{oes}	Output Capacitance			-	470	-	pF
C_{res}	Reverse Transfer Capacitance			-	16	-	pF
Q_g	Total Gate Charge	V_{GE}=15V, V_{CE}=480V, I_C=75A		-	118	-	nC
Q_{ge}	Gate to Emitter Charge			-	48	-	nC
Q_{gc}	Gate to Collector Charge			-	36	-	nC
$I_{C(SC)}$	Short circuit collector current, Max. 1000 short circuits, Delay between short circuits ⩾ 1.0s	V_{GE}=15V, V_{CE}=400V, R_G=25Ω		-	290	-	A
R_g	Gate resistance	V_{GE}=0V, V_{CE}=0V, f=1MHz		-	1.5	-	Ω
SWITCHING PARAMETERS, (Load Inductive, T_J=25°C)							
$t_{D(on)}$	Turn-On DelayTime	T_J=25°C V_{GE}=15V, V_{CE}=400V, I_C=75A, R_G=4Ω, Parasitic Inductance=150nH		-	33	-	ns
t_r	Turn-On Rise Time			-	69	-	ns
$t_{D(off)}$	Turn-Off Delay Time			-	84	-	ns
t_f	Turn-Off Fall Time			-	18.4	-	ns
E_{on}	Turn-On Energy			-	3.7	-	mJ
E_{off}	Turn-Off Energy			-	1.3	-	mJ
E_{total}	Total Switching Energy			-	5	-	mJ
t_{rr}	Diode Reverse Recovery Time	T_J=25°C I_F=37.5A,dI/dt=200A/µs,V_{CE}=400V		-	147	-	ns
Q_{rr}	Diode Reverse Recovery Charge			-	0.9	-	µC
I_{rm}	Diode Peak Reverse Recovery Current			-	10	-	A
SWITCHING PARAMETERS, (Load Inductive, T_J=175°C)							
$t_{D(on)}$	Turn-On DelayTime	T_J=175°C V_{GE}=15V, V_{CE}=400V, I_C=75A, R_G=4Ω, Parasitic Inductance=150nH		-	37	-	ns
t_r	Turn-On Rise Time			-	67	-	ns
$t_{D(off)}$	Turn-Off Delay Time			-	135	-	ns
t_f	Turn-Off Fall Time			-	20	-	ns
E_{on}	Turn-On Energy			-	3.8	-	mJ
E_{off}	Turn-Off Energy			-	2	-	mJ
E_{total}	Total Switching Energy			-	5.8	-	mJ
t_{rr}	Diode Reverse Recovery Time	T_J=175°C I_F=37.5A,dI/dt=200A/µs,V_{CE}=400V		-	220	-	ns
Q_{rr}	Diode Reverse Recovery Charge			-	1.7	-	µC
I_{rm}	Diode Peak Reverse Recovery Current			-	13	-	A

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

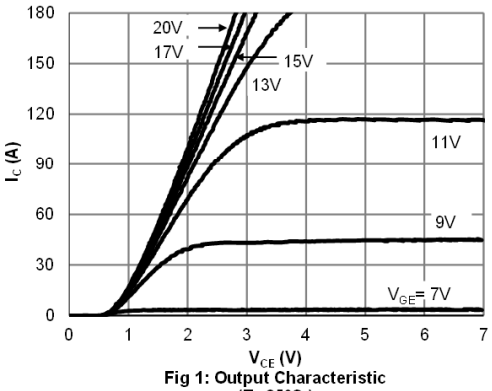


Fig 1: Output Characteristic (T_j=25°C)

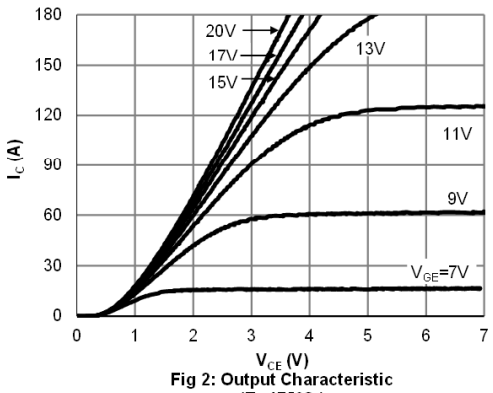


Fig 2: Output Characteristic (T_j=175°C)

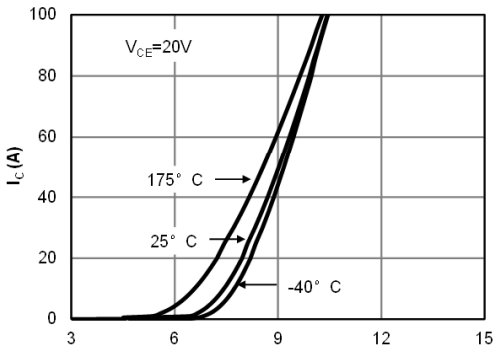


Fig 3: Transfer Characteristic

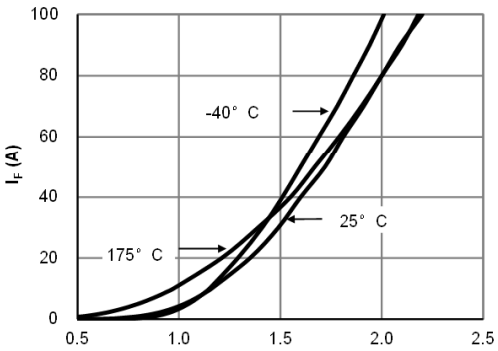


Fig 4: Diode Characteristic

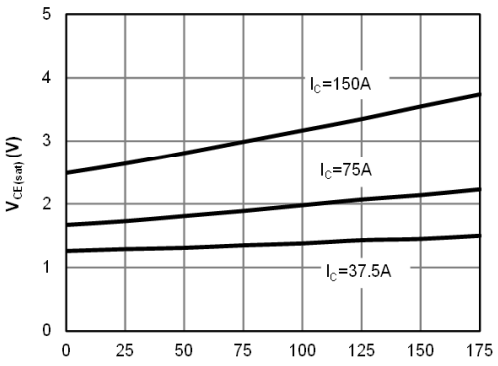


Fig 5: Collector-Emitter Saturation Voltage vs. Junction Temperature

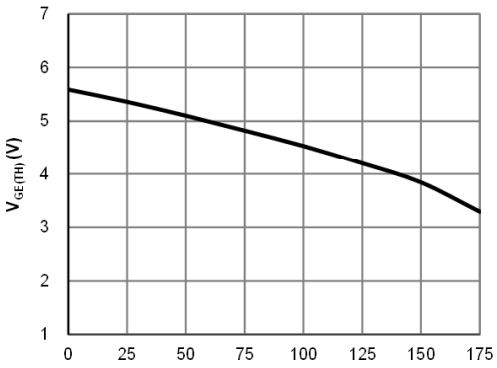


Figure 6: $V_{GE(TH)}$ vs. T_j

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

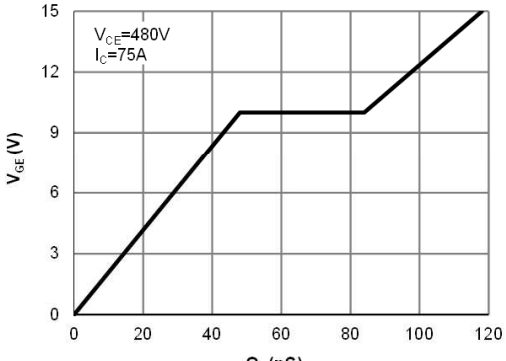


Fig 7: Gate-Charge Characteristics

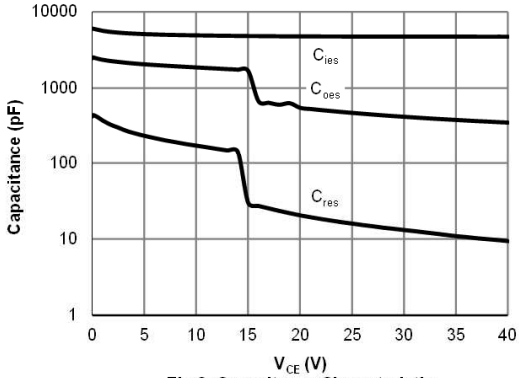


Fig 8: Capacitance Characteristic

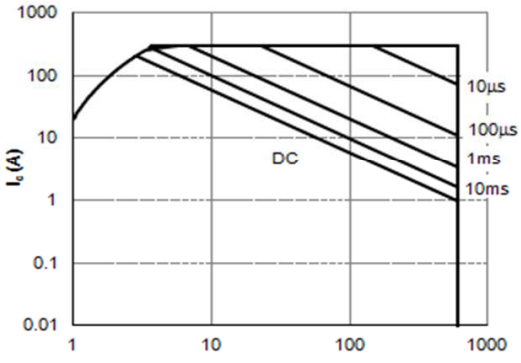


Fig 9: Forward Bias Safe Operating Area
(T_C=25C,V_{GE}=15V)

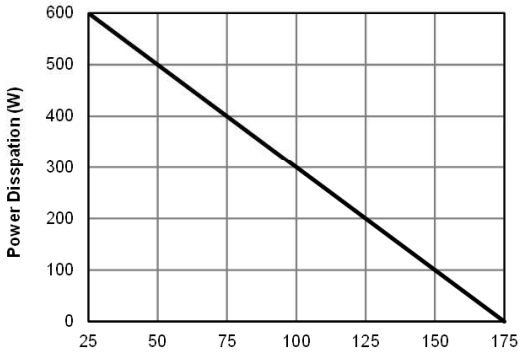


Fig 10: Power Disspation as a Function of Case

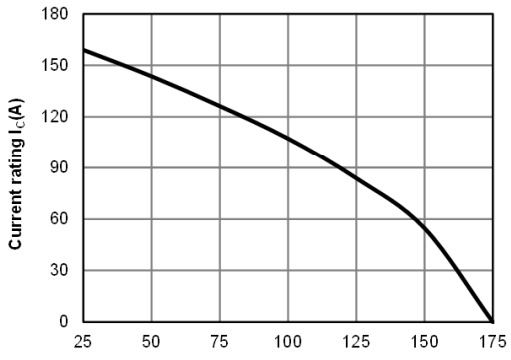


Fig 11: Current De-rating

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

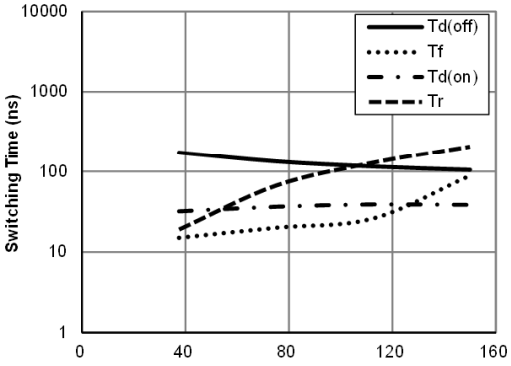


Figure 12: Switching Time vs. I_C
(T_j=175°C,V_{GE}=15V,V_{CE}=400V,R_g=4Ω)

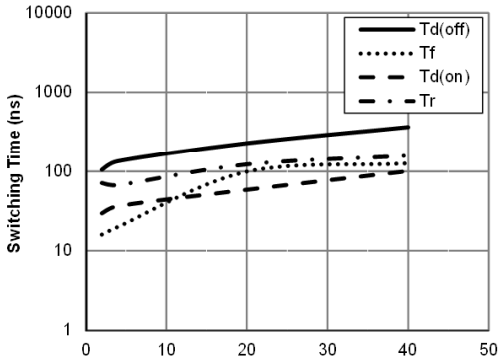


Figure 13: Switching Time vs. R_g
(T_j=175°C,V_{GE}=15V,V_{CE}=400V,I_C=75A)

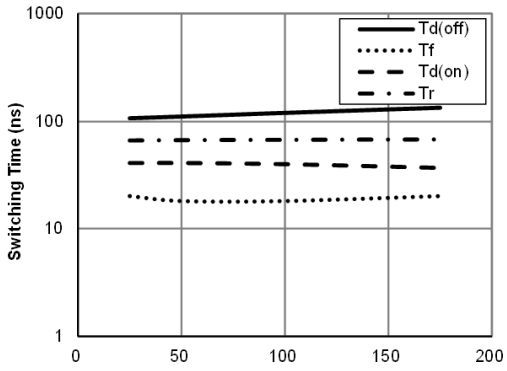


Figure 14: Switching Time vs.T_j
(V_{GE}=15V,V_{CE}=400V,I_C=75A,R_g=4Ω)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

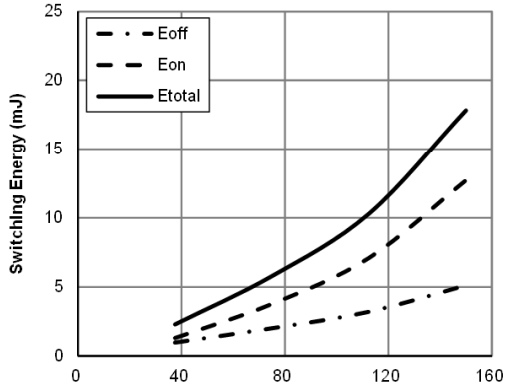


Figure 15: Switching Loss vs. I_C
(T_j=175°C,V_{GE}=15V,V_{CE}=400V,R_g=4Ω)

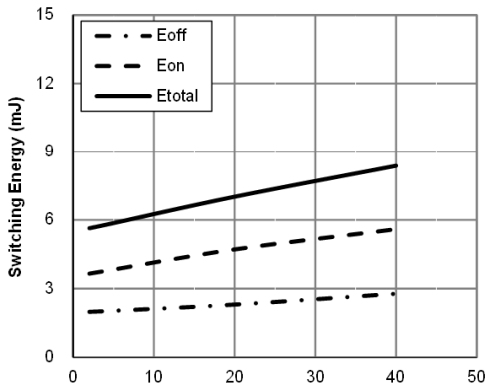


Figure 16: Switching Loss vs. R_g
(T_j=175°C,V_{GE}=15V,V_{CE}=400V,I_C=75A)

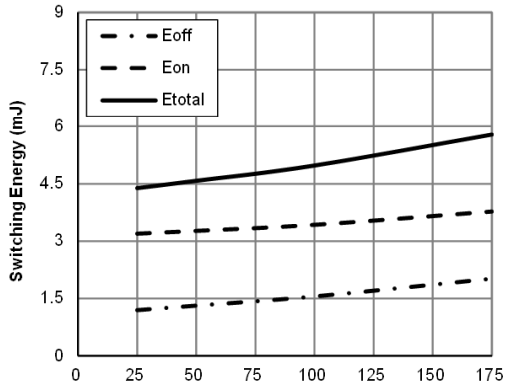


Figure 17: Switching Loss vs. T_j
(V_{GE}=15V,V_{CE}=400V,I_C=75A,R_g=4Ω)

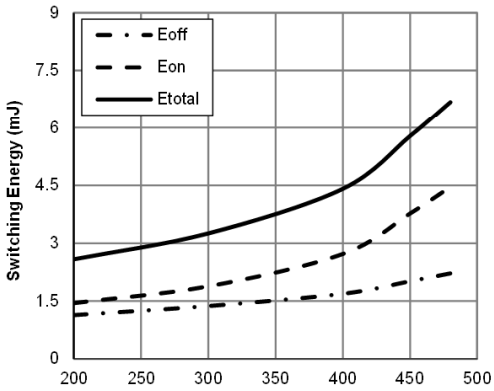


Figure 18: Switching Loss vs. V_{CE}
(T_j=175°C,V_{GE}=15V,I_C=75A,R_g=4Ω)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

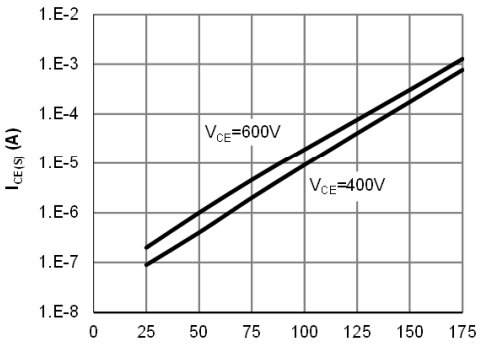


Fig 19: Diode Reverse Leakage Current vs. Junction Temperature

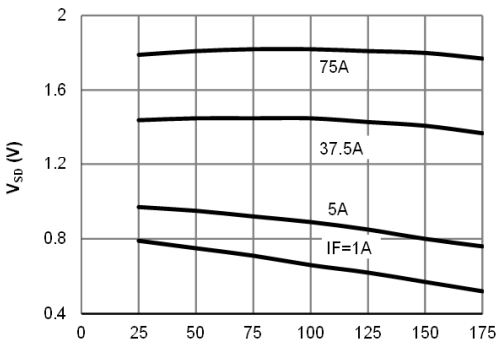


Fig 20: Diode Forward voltage vs. Junction Temperature

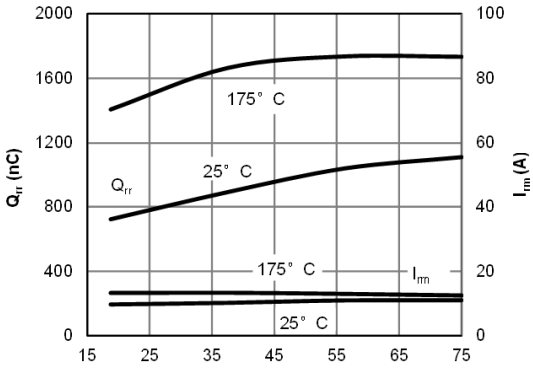


Fig 21: Diode Reverse Recovery Charge and Peak Current vs. Conduction Current
(V_{GE}=15V,V_{CE}=400V, di/dt=200A/µs)

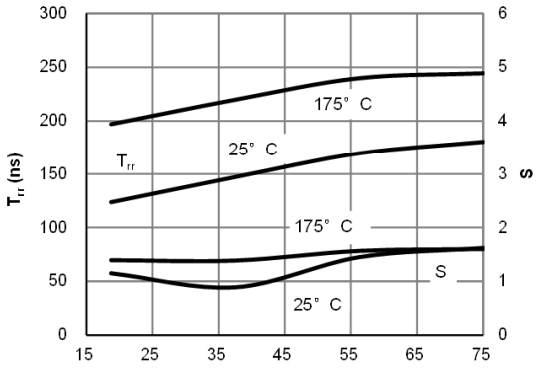


Fig 22: Diode Reverse Recovery Time and Softness Factor vs. Conduction Current
(V_{GE}=15V,V_{CE}=400V, di/dt=200A/µs)

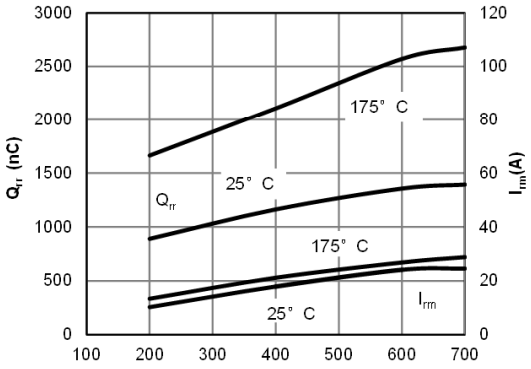


Fig 23: Diode Reverse Recovery Charge and Peak Current vs. di/dt
(V_{GE}=15V,V_{CE}=400V,I_F=37.5A)

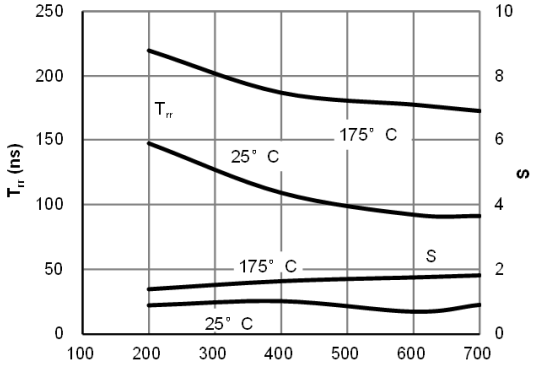


Fig 24: Diode Reverse Recovery Time and Softness Factor vs. di/dt
(V_{GE}=15V,V_{CE}=400V,I_F=37.5A)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

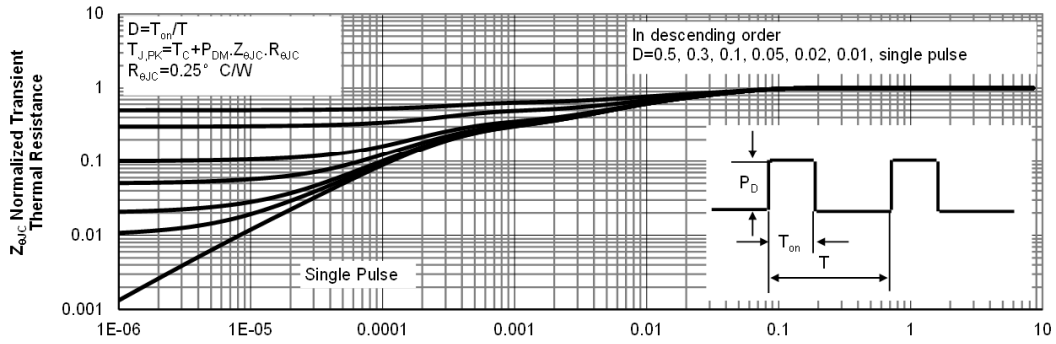


Figure 25: Normalized Maximum Transient Thermal Impedance for IGBT

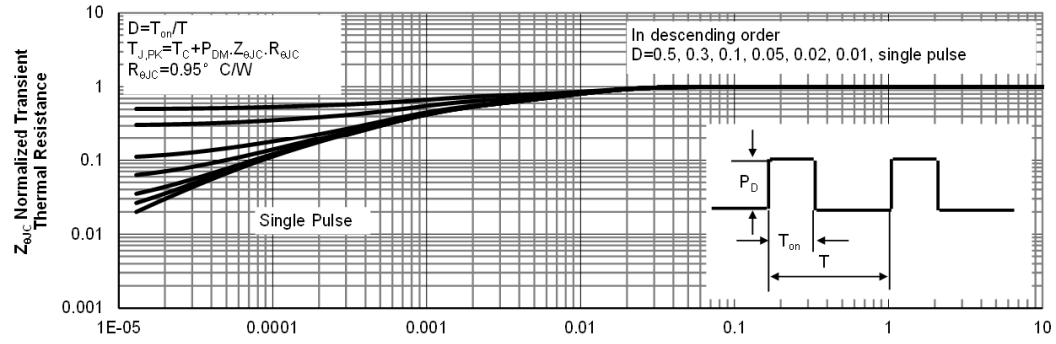


Figure 26: Normalized Maximum Transient Thermal Impedance for Diode

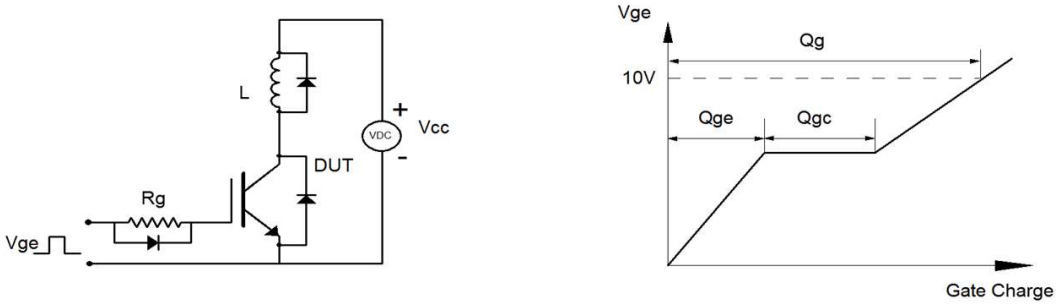


Figure A: Gate Charge Test Circuit & Waveforms

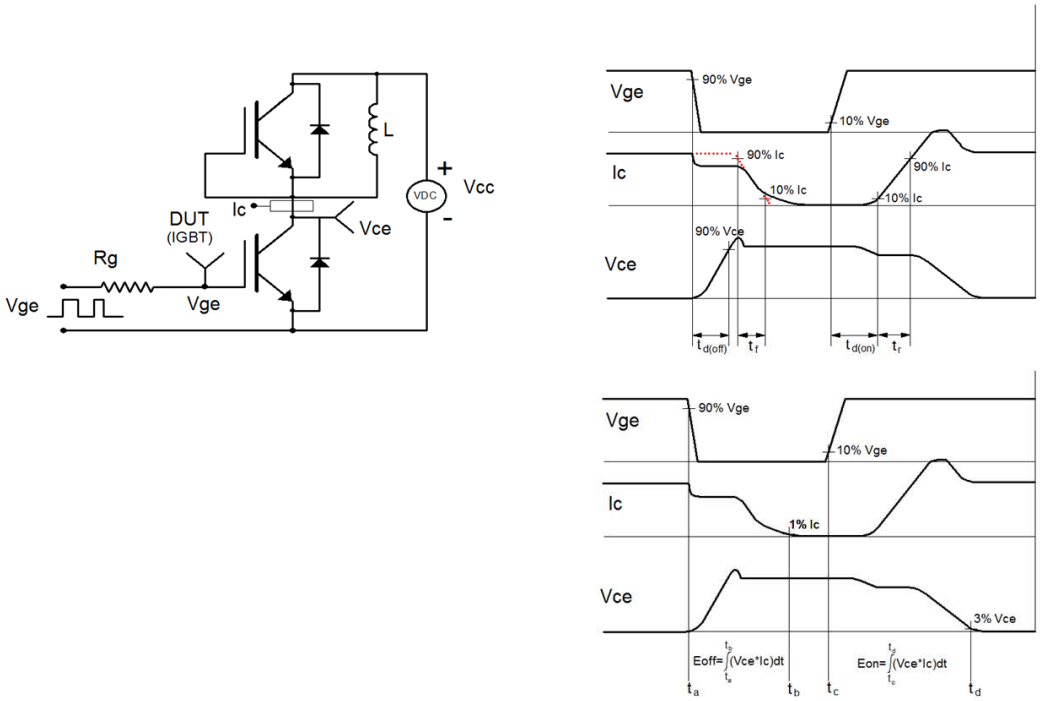


Figure B: Inductive Switching Test Circuit & Waveforms

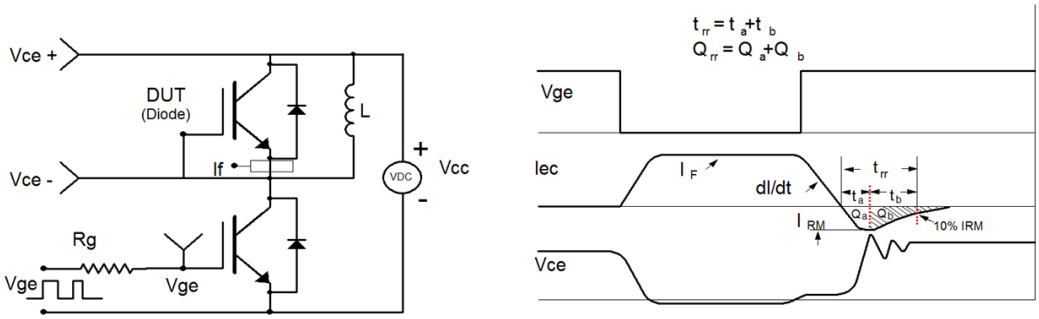


Figure C: Diode Recovery Test Circuit & Waveforms